

# STD19N3LLH6AG

# Automotive-grade N-channel 30 V, 25 mΩ typ., 10 A STripFET™ H6 Power MOSFET in a DPAK package

Datasheet - production data

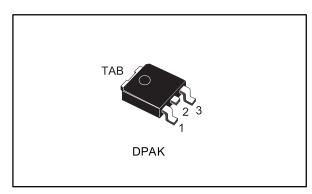
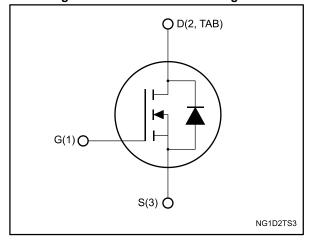


Figure 1: Internal schematic diagram



## **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>	Ртот
STD19N3LLH6AG	30 V	33 mΩ	10 A	30 W

- Designed for automotive applications and AEC-Q101 qualified
- Very low on-resistance
- Very low gate charge
- High avalanche ruggedness
- Low gate drive power loss
- Logic level

## **Applications**

• Switching applications

## Description

This device is an N-channel Power MOSFET developed using the STripFET™ H6 technology with a new trench gate structure. The resulting Power MOSFET exhibits very low R<sub>DS(on)</sub> in all packages.

**Table 1: Device summary** 

Order code	Marking	Package	Packing
STD19N3LLH6AG	19N3LLH6	DPAK	Tape and reel

Contents STD19N3LLH6AG

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STD19N3LLH6AG Electrical ratings

# 1 Electrical ratings

**Table 2: Absolute maximum ratings** 

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage	30	V
$V_{GS}$	Gate-source voltage	±20	V
	Drain current (continuous) at T <sub>case</sub> = 25 °C <sup>(1)</sup>	10	Δ
I <sub>D</sub>	Drain current (continuous) at T <sub>case</sub> = 100 °C	10	A
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	40	Α
Ртот	Total dissipation at T <sub>case</sub> = 25 °C	30	W
T <sub>stg</sub>	Storage temperature	55 1- 475	
Tj	Operating junction temperature	-55 to 175	°C

### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case	5	۰۵۸۸
R <sub>thj-pcb</sub> <sup>(1)</sup>	Thermal resistance junction-pcb	50	°C/W

#### Notes:

**Table 4: Avalanche characteristics** 

Symbol	Parameter	Value	Unit
I <sub>AV</sub> <sup>(1)</sup>	Avalanche current, repetitive or not repetitive	10	Α
E <sub>AS</sub> <sup>(2)</sup>	Single pulse avalanche energy	130	mJ

### Notes:

 $<sup>^{(1)}</sup>$  Current limited by package. At  $T_{case}$  = 25  $^{\circ}$ C the silicon is able to sustain 22 A.

<sup>(2)</sup> Pulse width limited by safe operating area.

<sup>&</sup>lt;sup>(1)</sup>When mounted on a 1-inch² FR-4, 2 Oz copper board.

 $<sup>^{\</sup>left(1\right)}$  Pulse width limited by  $T_{jmax}.$ 

 $<sup>^{(2)}</sup>$  starting  $T_j$  = 25 °C,  $I_D$  =  $I_{AV},\,V_{DD}$  = 25 V.

## 2 Electrical characteristics

(T<sub>case</sub> = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	30			V
	Zana mata walta na duain	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 30 V			1	μΑ
I <sub>DSS</sub>	I <sub>DSS</sub> Zero gate voltage drain current	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 30 V, T <sub>case</sub> = 125 °C			100	μΑ
Igss	Gate-body leakage current	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = ±20 V			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1		2.5	V
R <sub>DS(on)</sub>	Static drain-source on- resistance	$V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		25	33	mΩ
		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 5 A		33	50	11122

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	321	ı	
Coss	Output capacitance	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz},$	-	68	ı	pF
Crss	Reverse transfer capacitance	Ves = 0 V	-	34	ı	Pi
$Q_g$	Total gate charge	$V_{DD} = 15 \text{ V}, I_D = 10 \text{ A},$	-	3.7	ı	
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> = 4.5 V (see Figure 14: "Test circuit for gate charge	-	1	ı	nC
$Q_{gd}$	Gate-drain charge	behavior")	-	1.7	-	

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Uni t	
t <sub>d(on)</sub>	Turn-on delay time	$V_{DD} = 15 \text{ V}, I_D = 5 \text{ A}$	-	2.4	-		
t <sub>r</sub>	Rise time	$R_G = 4.7 \Omega$ , $V_{GS} = 10 V$ (see Figure 13: "Test circuit for	-	2.5	-		
t <sub>d(off)</sub>	Turn-off delay time	resistive load switching times"	-	12.8	1	ns	
t <sub>f</sub>	Fall time	and Figure 18: "Switching time waveform")	-	2.5	-		

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		ı		10	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		1		40	А
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 10 A	ı		1.12	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 10 A, di/dt = 100 A/µs,	ı	15.1		ns
Qrr	Reverse recovery charge	V <sub>DD</sub> = 24 V (see Figure 15: "Test circuit for inductive load	-	7.5		nC
IRRM	Reverse recovery current	switching and diode recovery times")	-	1		А

## Notes:

<sup>&</sup>lt;sup>(1)</sup> Pulse width is limited by safe operating area.

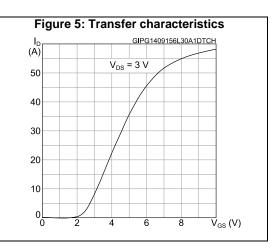
 $<sup>^{(2)}</sup>$  Pulse test: pulse duration = 300  $\mu s,$  duty cycle 1.5%.

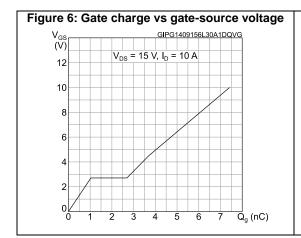
# 2.1 Electrical characteristics (curves)

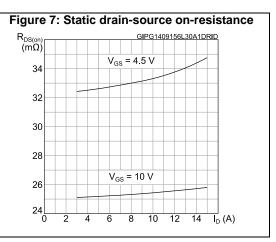
Figure 2: Safe operating area GIPG1409156L30A1DSOA (A) Operation in this area is limited by  $R_{DS(nn)}$  100  $\mu$ s 1 ms 1 ms 10 ms 10 ms 10 ms 10 ms 10 ms

Figure 3: Thermal impedance  $K \\ \delta = 0.5 \\ \delta = 0.2 \\ \delta = 0.05 \\ \delta = 0.01 \\ \delta = 0.01 \\ \delta = 0.01 \\ Single pulse \\ 10^{-2} \\ 10^{-5} \\ 10^{-4} \\ 10^{-3} \\ 10^{-2} \\ t_p (s)$ 

Figure 4: Output characteristics GIPG1409156L30A1DOCH V<sub>GS</sub> = 8,9,10 V 50  $V_{GS} = 7 V$  $V_{GS} = 6 V$ 40  $V_{GS} = 5 V$ 30 20  $V_{GS} = 4 V$ 10  $V_{GS} = 3 V$ 2.5 0.5 1.0 1.5 2.0







STD19N3LLH6AG Electrical characteristics

Figure 8: Capacitance variations

C
GIPG1409156L30A1DCVR

(pF)

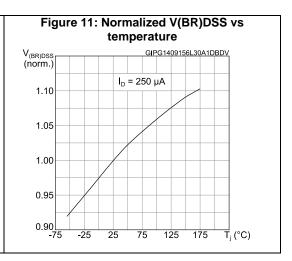
C
(pF)

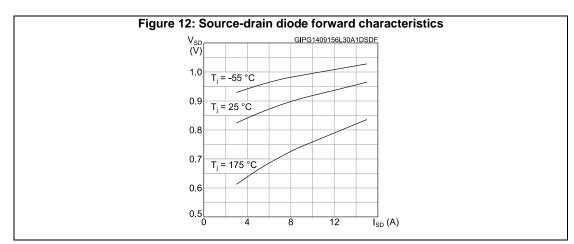
C
(pF)

C
(pF)

C
(pS)

Figure 9: Normalized gate threshold voltage vs temperature V<sub>GS(th)</sub> (norm.) GIPG1409156L30A1DVTH I<sub>D</sub> = 250 μA 1.1 1.0 0.9 0.8 0.7 0.6 0.5 -75 175 25 75 125 T<sub>i</sub> (°C)

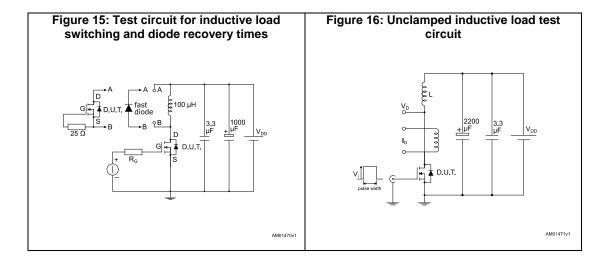


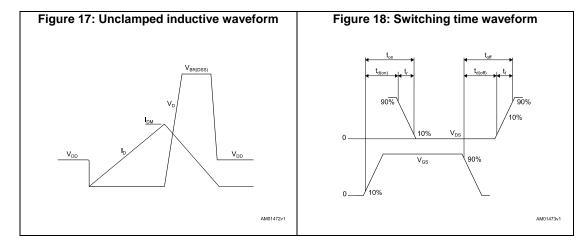


**Test circuits** STD19N3LLH6AG

#### 3 **Test circuits**

Figure 13: Test circuit for resistive load Figure 14: Test circuit for gate charge switching times behavior ⊥ 100 nF 2200 µF I<sub>G</sub>= CONST 2.7 kΩ 47 kΩ





1 kΩ

# 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

## 4.1 DPAK (TO-252) type A package information

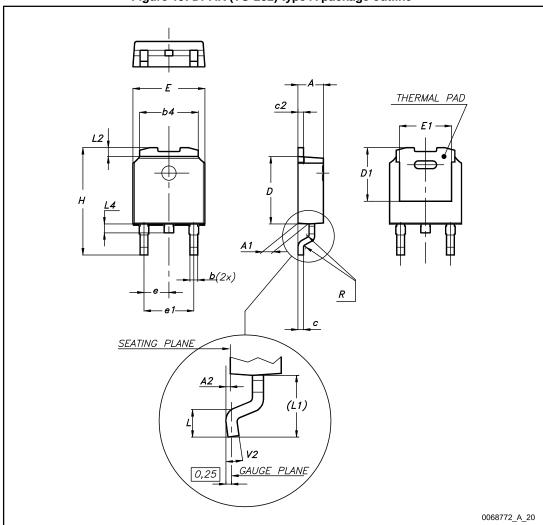
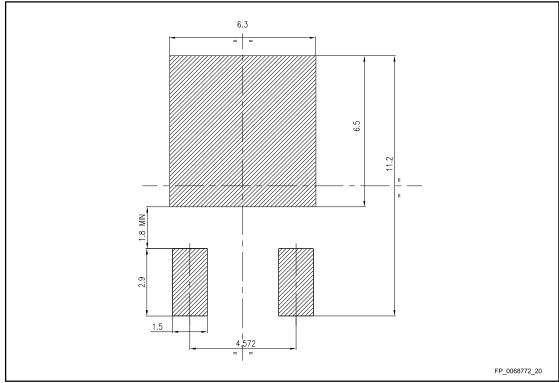


Figure 19: DPAK (TO-252) type A package outline

Table 9: DPAK (TO-252) type A mechanical data

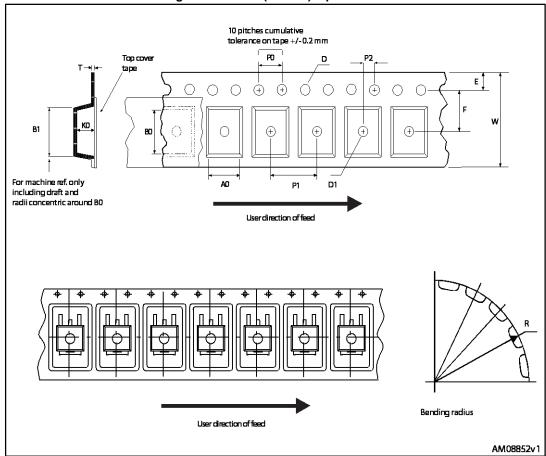
Table 3. bi Art (10-202) type A mechanical data					
Dim.		mm			
Diiii.	Min.	Тур.	Max.		
A	2.20		2.40		
A1	0.90		1.10		
A2	0.03		0.23		
b	0.64		0.90		
b4	5.20		5.40		
С	0.45		0.60		
c2	0.48		0.60		
D	6.00		6.20		
D1	4.95	5.10	5.25		
E	6.40		6.60		
E1	4.60	4.70	4.80		
е	2.16	2.28	2.40		
e1	4.40		4.60		
Н	9.35		10.10		
L	1.00		1.50		
(L1)	2.60	2.80	3.00		
L2	0.65	0.80	0.95		
L4	0.60		1.00		
R		0.20			
V2	0°		8°		

Figure 20: DPAK (TO-252) recommended footprint (dimensions are in mm)



# 4.2 DPAK (TO-252) packing information

Figure 21: DPAK (TO-252) tape outline



A 40mm min. access hole at slot location

Tape slot in core for tape start 2.5mm min.width

AM06038v1

Figure 22: DPAK (TO-252) reel outline

Table 10: DPAK (TO-252) tape and reel mechanical data

Таре			Reel		
Dim	n	ım	Dim.	r	nm
Dim.	Min.	Max.	Dilli.	Min.	Max.
A0	6.8	7	А		330
В0	10.4	10.6	В	1.5	
B1		12.1	С	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	Т		22.4
K0	2.55	2.75			
P0	3.9	4.1	Bas	e qty.	2500
P1	7.9	8.1	Bul	k qty.	2500
P2	1.9	2.1			
R	40				
Т	0.25	0.35			
W	15.7	16.3			

Revision history STD19N3LLH6AG

# 5 Revision history

**Table 11: Document revision history** 

Date	Revision	Changes
01-Oct-2015	1	Initial version
13-Oct-2015	2	On cover page: - updated title In section Electrical characteristics: - updated table Dynamic Updated section Test circuits

### **IMPORTANT NOTICE - PLEASE READ CAREFULLY**

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